Search Notes				
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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/761,281	YIP ET AL.	
Examiner	Art Unit	
Afsar M. Qureshi	2667	

SEARCHED				
Class	Subclass	Date	Examiner	
370	392	8/19/2005	AQ	
	295.32			
	395.5			
	395.52			
	400			
	401			
	409	•		
-	428			
	465			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
See interference search history			

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST/IEEE (see search history)	8/19/2005	AQ